

<b>Notice of References Cited</b>	Application/Control No. 10/537,893		Applicant(s)/Patent Under Reexamination MATHIEU ET AL.	
	Examiner Toan M. Le		Art Unit 2863	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,517,835	05-1985	Kerzner, Mark G.	73/152.02
*	B	US-5,960,371	09-1999	Saito et al.	702/11
*	C	US-2003/0165256	09-2003	Ginkel et al.	382/109
*	D	US-4,357,660	11-1982	Hepp, Vincent R.	702/10
*	E	US-4,414,656	11-1983	Hepp, Vincent R.	367/25
*	F	US-5,581,024	12-1996	Meyer et al.	73/152.03
*	G	US-4,440,020	04-1984	Boutemy et al.	73/152.02
*	H	US-4,453,219	06-1984	Clavier et al.	702/10
*	I	US-4,320,469	03-1982	Frawley et al.	367/33
*	J	US-4,117,600	10-1978	Guignard et al.	33/735
*	K	US-4,303,975	12-1981	Hepp, Vincent R.	702/10
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.